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2003 International Workshop on Memory Technology, Design and Testing (MTDT 2003)

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Program Introduction: T. Wik, Program Chair
MTDT Message: Adit Singh, General Chair

Keynote Address

Platform Architecture and the Persistence of Memory
Christopher Hamlin, Chief Technology Officer, LSI Logic

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Chair: Robert Evans, MOSAID

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Chair: Eric Dupont, iROC Technology

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Chair and Moderator: R. Dean Adams, PDAT Technologies

Panelists: Michael Nicolaidis, iROC
Steve Pateras, Logic Vision
Wu-Tung Cheng, Mentor Graphics
Shahryar Arani, Virage Logic

Session 5: Memory Roadmap, Yield and Optimization

Chair: Ad van de Goor, Delft University of Technology

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Panel: Embedded DRAM
Moderator: Bruce Cockburn, University of Alberta
Panelists: TBD

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